

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/692,894	HWANG ET AL.	
Examiner		Art Unit		Page 1 of 1
Emmanuel Bayard		2611		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0021355	01-2003	You, Cheol Woo	375/267
*	B	US-6,678,263	01-2004	Hammons et al.	370/342
*	C	US-2002/0044591	04-2002	Lee et al.	375/130
*	D	US-2002/0101908	08-2002	Kim et al.	375/147
*	E	US-2003/0174782	09-2003	Papadias et al.	375/295
*	F	US-2003/0086479	05-2003	Naguib, Ayman F.	375/144
*	G	US-2004/0120411	06-2004	Walton et al.	375/260
*	H	US-2004/0137864	07-2004	Hwang et al.	455/130
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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